Application/Con Applicant(s)/Patent Under Reexamination NI ET AL. Examiner Art Unit Page 1 of 1

Luz L. Aleiandro

Notice of References Cited

U.S. PATENT DOCUMENTS									
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification				
	Α	US-5,824,602	10-1998	Molvik et al.	118/723AN				
	В	US-5,807,789	09-1998	Chen et al.	438/424				
	С	US-							
	D	US-							
	Е	US-							
	F	US-							
	G	US-							
	Н	US-							
	1	US-		;					
	J	US-							
	κ	US-							
	L	US-							
	М	US-							

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 0058992	10-2000	PCT	Howald et al.	
	0					
	Р					
	α				·	
	Ŗ					
	S			:		
	T					

NON-PATENT DOCUMENTS

_									
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)							
	υ								
	V		T						
	w								
	X								

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.